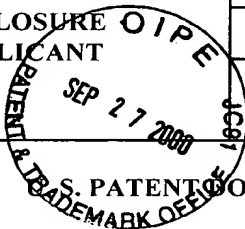


PTO-1449  INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 2298/3	SERIAL NO. 09/492,173
	APPLICANT - Hideki Ito INUYAMA-SHI <i>et al</i>	
	FILING DATE January 27, 2000	GROUP 5727-1772



EXAMINER R INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS/SUBCLASS

#### FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION	
					YES	NO
<i>M.P.</i>	EP 0 826,482	<i>5/18/88</i>	<i>EPO</i>	<i>—</i>		<input checked="" type="checkbox"/>
<i>M.P.</i>	EP 0 271 928	<i>12/18/87</i>	<i>EPO</i>	<i>—</i>		<input checked="" type="checkbox"/>
<i>M.P.</i>	EP 0210,646	<i>2/4/87</i>	<i>EPO</i>	<b>RECEIVED</b> <b>OCT 3 2000</b> <b>GROUP 1700</b>		<input checked="" type="checkbox"/>
<i>M.P.</i>	EP 0 267,799	<i>3/4/98</i>	<i>EPO</i>			<input checked="" type="checkbox"/>
<i>M.R.</i>	EP 0 934,813	<i>8/11/99</i>	<i>EPO</i>			<input checked="" type="checkbox"/>

#### OTHER

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION	
					YES	NO
<i>M.P.</i>	European Search Report	08/23/00				<input checked="" type="checkbox"/>

EXAMINER <i>Monica Patterson</i>	DATE CONSIDERED <i>8/8/02</i>
EXAMINER: Initial if citation is considered, whether or not citation is in conformance with M.P.E.P. 609; strike out citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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**FORM PTO-1449**  
**INFORMATION DISCLOSURE**  
**STATEMENT BY APPLICANT(S)**

Atty Docket No. : 02298/3  
 Serial No. : 09/492,173  
 Inventors : Hideki ITO et al.  
 Filed : 27 Jan. 2000  
 Group Art Unit : 3727  
 Examiner :



**U.S. PATENT DOCUMENTS**

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
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**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No
<i>M.P.</i>	5-254015	10/05/93	Japan		X
<i>M.P.</i>	8-239460	09/17/96	Japan		X
<i>M.P.</i>	9-052965	02/25/97	Japan		X
<i>M.P.</i>	10-077335	03/24/98	Japan		X
<i>M.P.</i>	6-345878	12/20/94	Japan		X
<i>M.P.</i>	2000-218694	08/08/00	Japan		X
<i>M.P.</i>	2000-309646	11/07/00	Japan		X
<i>M.P.</i>	2000-309647	11/07/00	Japan		X
<i>M.P.</i>	2000-301609	10/31/00	Japan		X

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**OTHER DOCUMENTS**

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